

What is claimed is:

1. A diaphragm edge of a speaker, which is formed by compressing a material including silicon rubber and has an emboss on a front surface thereof.

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2. The diaphragm edge of claim 1, wherein the diaphragm edge comprises a first adhesion portion disposed at an inner circumference thereof, a second adhesion portion disposed at an outer circumference thereof, and a roll disposed between the first and second adhesion portions, and

10 wherein the roll is one of an up-roll, a down-roll, an N-roll, an M-roll and a W-roll, and a line is formed on a lower surface of the roll to be convex and parallel to the inner or outer circumference.

15 3. The diaphragm edge of claim 2, wherein a width of the line is between 0.2 mm - 1.4 mm and the maximum height of the line from the lower surface is 0.2 mm - 1.3 mm.

20 4. The diaphragm edge of claim 1, wherein the emboss has an arithmetical mean deviation from the mean line of the profile (Ra) between 2.44  $\mu\text{m}$  - 28.70  $\mu\text{m}$ , a maximum height (Ry) between 14.25  $\mu\text{m}$  - 120.00  $\mu\text{m}$ , and a ten point average roughness (Rz) between 7.90  $\mu\text{m}$  - 97.00  $\mu\text{m}$ .

25 5. A diaphragm edge of a speaker, which is formed by compressing a material including silicon rubber and powdered viscose rayon and has an emboss on a front surface thereof.

30 6. The diaphragm edge of claim 5, wherein the emboss has an arithmetical mean deviation from the mean line of the profile (Ra) between 2.44  $\mu\text{m}$  - 28.70  $\mu\text{m}$ , a maximum height (Ry) between 14.25  $\mu\text{m}$  - 120.00  $\mu\text{m}$ , and a ten point average roughness (Rz) between 7.90  $\mu\text{m}$  - 97.00  $\mu\text{m}$ .

7. The diaphragm edge of claim 5, wherein the viscose rayon is powdered to have a length between 0.1 mm - 3.0 mm.

8. The diaphragm edge of claim 7, wherein the emboss has an arithmetical mean deviation from the mean line of the profile (Ra) between 2.44  $\mu\text{m}$  - 28.70  $\mu\text{m}$ , a maximum height (Ry) between 14.25  $\mu\text{m}$  - 120.00  $\mu\text{m}$ , and a ten point average roughness (Rz) between 7.90  $\mu\text{m}$  - 97.00  $\mu\text{m}$ .

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9. The diaphragm edge of claim 5, wherein the weight ratio between the silicon rubber and the viscose rayon is 100:3.

10 10. The diaphragm edge of claim 9, wherein the emboss has an arithmetical mean deviation from the mean line of the profile (Ra) between 2.44  $\mu\text{m}$  - 28.70  $\mu\text{m}$ , a maximum height (Ry) between 14.25  $\mu\text{m}$  - 120.00  $\mu\text{m}$ , and a ten point average roughness (Rz) between 7.90  $\mu\text{m}$  - 97.00  $\mu\text{m}$ .

15 11. The diaphragm edge of claim 5, wherein the diaphragm edge comprises a first adhesion portion disposed at an inner circumference thereof, a second adhesion portion disposed at an outer circumference thereof, and a roll disposed between the first and second adhesion portions, and

20 wherein the roll is one of an up-roll, a down-roll, an N-roll, an M-roll and a W-roll, and a line is formed on a lower surface of the roll to be convex and parallel to the inner or outer circumference.

12. The diaphragm edge of claim 11, wherein a width of the line is between 0.2 mm - 1.4 mm and the maximum height of the line from the lower surface is 0.2 mm - 1.3 mm.

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13. The diaphragm edge of claim 12, wherein the emboss has an arithmetical mean deviation from the mean line of the profile (Ra) between 2.44  $\mu\text{m}$  - 28.70  $\mu\text{m}$ , a maximum height (Ry) between 14.25  $\mu\text{m}$  - 120.00  $\mu\text{m}$ , and a ten point average roughness (Rz) between 7.90  $\mu\text{m}$  - 97.00  $\mu\text{m}$ .